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Ceramic transient voltage suppressors

SMD disk varistors for telecom applications

Series/Type:

Date: November 2010

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Telecom series

<u>SMD</u>

EPCOS type designation system for SMD disk varistor telecom series

CU	4032	S	95	А	G2
Construction: CU ≜ Encapsulated chip					
Case sizes: 4032 ≙ 40 x 32					
Varistor voltage tolerance: S \triangleq Special tolerance					
Maximum RMS operating voltage (V, $60 \triangleq 60 \text{ V}$ $95 \triangleq 95 \text{ V}$	_{RMS}):				
$\textbf{A} \triangleq \textbf{Special tolerance}$					
Taping mode: G2 ≙ Taped, 330-mm reel					

Telecom series

SMD

Features

- High surge voltage capability up to 2 kV for 10/700 µs (acc. to German telecom administration standards)
- High surge load capability acc. to IEC 61000-4-5
- Matched to line conditions with or without superimposed ringing voltages
- PSpice models available
- RoHS-compatible

Applications

- EMI protection for:
 - Line cards in switching exchange systems
 - Terminal devices such as telephones, fax, modems
 - xDSL, PBX, DECT lines

Design

- Cylindrical varistor element, encapsulated.
- Encapsulation: thermoplastic, flame-retardant to UL 94 V-0.
- Termination: tinned copper alloy, suitable for lead-free wave and reflow soldering, and compatible with tin/lead solder.

V/I characteristics and derating curves

V/I and derating curves are attached to the data sheet. The curves are sorted by V_{RMS} and then by case size, which is included in the type designation.

General technical data

Maximum RMS operating voltage		$V_{\text{RMS,max}}$	60 95	V
Maximum DC operating voltage		$V_{\text{DC,max}}$	85 125	V
Maximum surge current	(10 pulses, 10/700 µs)	I _{surge,max}	45	А
Maximum energy absorption	(2 ms)	W _{max}	4800 7600	mJ
Maximum clamping voltage	(8/20 µs)	V _{clamp,max}	200 270	V
Operating temperature		T _{op}	-40/+85	°C
Storage temperature		LCT/UCT	-40/+125	°C





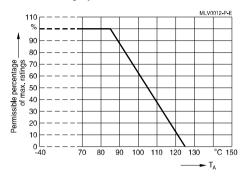


Telecom series

<u>SMD</u>

Temperature derating

Climatic category: -40/+85 °C



Electrical specifications and ordering codes Maximum ratings (T $_{\rm op,max}$ = 85 $^{\circ}{\rm C}$)

Туре	Ordering code	$V_{\text{RMS,max}}$	$V_{\text{DC,max}}$	I _{surge,max}	I _{surge,max}	W _{max}	$P_{diss,max}$
				(10 pulses,	(8/20 µs)	(2 ms)	
				10/700 µs)			
		V	V	A	A	mJ	mW
CU4032S60AG2	B72660M0600S172	60	85	45	1200	4800	250
CU4032S95AG2	B72660M0950S172	95	125	45	1200	7600	250

Characteristics (T_A = 25 °C)

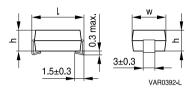
Туре	V _v (1 mA)	ΔV_V	V _{clamp,max}	I _{clamp} (8/20 μs)	C _{typ} (1 kHz, 1 V)
	V	%	V	А	pF
CU4032S60AG2	100	+18/-1	200	45	480
CU4032S95AG2	150	+10/-2	270	45	260



Telecom series

<u>SMD</u>

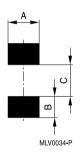
Dimensional drawing



Dimensions in mm

Chip size	$V_{\text{RMS,max}}$	I	w	h
EIA in mm				
4032	60, 95	$10.2 \pm \! 0.3$	8.0 ±0.3	3.2 ± 0.3

Recommended solder pad layout



Dimensions in mm

Chip size	А	В	С
EIA in mm			
4032	3.50	2.80	6.50

Delivery mode

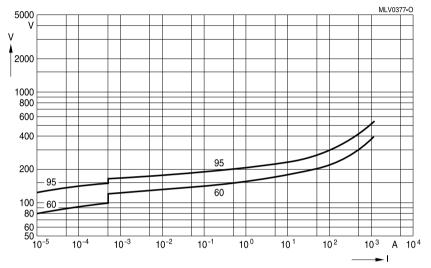
EIA case size	Taping	Reel size Packing unit		Туре	Ordering code	
		mm	pcs.			
4032	Blister	330	1000	CU4032S60AG2	B72660M0600S172	
4032	Blister	330	1000	CU4032S95AG2	B72660M0950S172	



Telecom series

<u>SMD</u>

V/I characteristics



CU4032S60A ... S95AG2



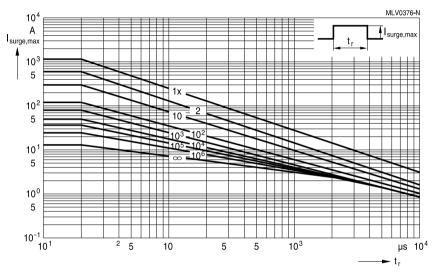
Telecom series

<u>SMD</u>

Derating curves

Maximum surge current $I_{surge,max} = f(t_r, pulse train)$

For explanation of the derating curves refer to "General technical information", chapter 2.7.2



CU4032S60AG2/S95AG2



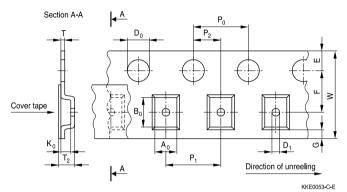
Telecom series

<u>SMD</u>

Taping and packing

1 Taping and packing for SMD components

1.1 Blister tape (the taping to IEC 60286-3)



Dimensions in mm

	8-mm tape					12-mm tape		16-mm tape		
	Case size (inch/mm)					Case size (inch/mm)		Case size (inch/mm)		Tolerance
_			0508/ 1220	0612/ 1632	1012/ 2532					
	0603/ 1608	0506/ 1216	0805/ 2012	1206/ 3216	1210/ 3225	1812/ 4532	2220/ 5750	3225	4032	
A ₀	0.9 ±0.10	1.50	1.60	1.90	2.80	3.50	5.10	7.00	8.60	±0.20
B ₀	1.75 ±0.10	1.80	2.40	3.50	3.50	4.80	6.00	8.70	10.60	±0.20
K ₀	1.0	1.0 0.80 1.80			2.60		5.00		max.	
Т	0.30			0.	30	0.	30	max.		
T ₂	1.3	1.20	2.	50		3.	50	5.	50	max.
D ₀			1.50			1.	50	1.	50	+0.10/-0
D ₁			1.00			1.	50	1.	50	min.
P_0			4.00			4.00		4.00		$\pm 0.10^{1)}$
P_2			2.00			2.	00	2.	00	±0.05
P ₁			4.00			8.	00	12	.00	±0.10
W	8.00					12	.00	16	.00	±0.30
Е	1.75					1.75		1.	75	±0.10
F	3.50					5.50		7.50		±0.05
G			0.75			0.	75	0.	75	min.

1) $\leq \pm 0.2$ mm over 10 sprocket holes.

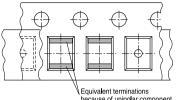


Telecom series

<u>SMD</u>

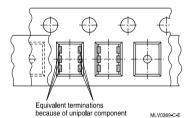
Part orientation in tape pocket for blister tape

For discrete chip, case sizes 0603, 0805, 1206, 1210, 1812 and 2220



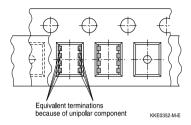
because of unipolar component KKE0351-A-E

For arrays 0506 and 1012

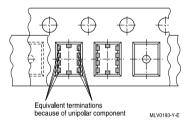


Additional taping information

For array, case sizes 0612



For filter array, case size 0508



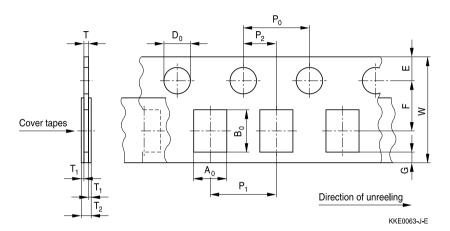
Additional taping information	
Reel material	Polystyrol (PS)
Tape material	Polystyrol (PS) or Polycarbonat (PC) or PVC
Tape break force	min. 10 N
Top cover tape strength	min. 10 N
Top cover tape peel force	0.2 to 0.6 N for 8-mm tape and 0.2 to 0.8 N for 12-mm tape at a peel speed of 300 mm/min
Tape peel angle	Angle between top cover tape and the direction of feed during peel off: 165° to 180°
Cavity play	Each part rests in the cavity so that the angle between the part and cavity center line is no more than 20°



Telecom series

<u>SMD</u>

1.2 Cardboard tape (taping to IEC 60286-3)



Dimensions in mm

	8-mm tape							
		Case size (inch/mm) Case si (inch/m						
	0201/0603	0402/1005 0405/1012 0603/1608 1003/2508 0508/1220						
A	0.38 ±0.05	0.60	1.05	0.95	1.00	1.60	±0.20	
B ₀	0.68 ±0.05	1.15	1.60	1.80	2.85	2.40	±0.20	
Т	0.35 ±0.02	0.60	0.60 0.75 0.95 1.00				max.	
T ₂	0.4 min.	0.70	0.70 0.90 1.10 1.10				max.	
D ₀	1.50 ±0.1		1.	50		1.50	+0.10/-0	
Po			4.	00			±0.10 ²⁾	
P ₂			2.	00			±0.05	
P ₁	2.00 ±0.05	2.00	4.00	4.00	4.00	4.00	±0.10	
W	8.00							
E	1.75							
F			3.	50			±0.05	
G	1.35			0.75			min.	

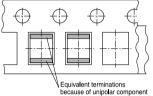
2) ≤ 0.2 mm over 10 sprocket holes.



Telecom series

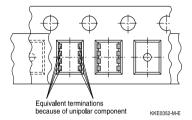
<u>SMD</u>

Part orientation in tape pocket for cardboard tape

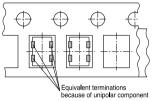




For array case size 0508

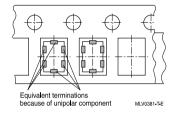


For array case size 0405



KKE0354-4-E

For filter array, case size 0405



Additional taping information

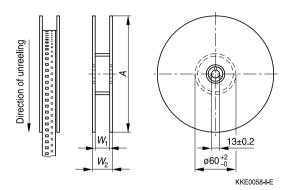
Reel material	Polystyrol (PS)
Tape material	Cardboard
Tape break force	min. 10 N
Top cover tape strength	min. 10 N
Top cover tape peel force	0.1 to 0.65 N at a peel speed of 300 mm/min
Tape peel angle	Angle between top cover tape and the direction of feed during peel off: 165° to 180°
Cavity play	Each part rests in the cavity so that the angle between the part and cavity center line is no more than 20°



Telecom series

<u>SMD</u>

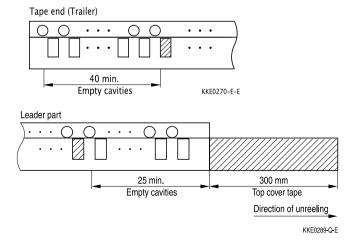
1.3 Reel packing



Dimensions in mm

	8-mn	n tape	12-mi	16-mm tape	
	180-mm reel	330-mm reel	180-mm reel	330-mm reel	330-mm reel
A	180 -3/+0	330 -2.0	180 -3/+0	330 -2.0	330 -2.0
W ₁	8.4 +1.5/-0	8.4 +1.5/-0	12.4 +1.5/-0	12.4 +1.5/-0	16.4 +1.5/-0
W ₂	14.4 max.	14.4 max.	18.4 max.	18.4 max.	22.4 max.

Leader, trailer



Telecom series

<u>SMD</u>

1.4 Packing units for discrete chip and array chip

	th the second se			180 mm	330 mm
Case size	Chip thickness	Cardboard tape	Blister tape	Ø 180-mm reel	Ø 330-mm reel
inch/mm	th	W	W	pcs.	pcs.
0201/0603	0.33 mm	8 mm	-	15000	-
0402/1005	0.6 mm	8 mm	_	10000	-
0405/1012	0.7 mm	8 mm	-	5000	-
0506/1216	0.5 mm	_	8 mm	4000	_
0508/1220	0.9 mm	8 mm	8 mm	4000	-
0603/1608	0.9 mm	8 mm	8 mm	4000	16000
0612/1632	0.9 mm	-	8 mm	3000	-
0805/2012	0.7 mm	_	8 mm	3000	_
	0.9 mm	-	8 mm	3000	12000
	1.3 mm	-	8 mm	3000	-
1003/2508	0.9 mm	8 mm	-	4000	-
1012/2532	1.0 mm	-	8 mm	2000	-
1206/3216	0.9 mm	-	8 mm	3000	—
	1.3 mm	-	8 mm	3000	—
	1.4 mm	-	8 mm	2000	—
	1.6 mm	-	8 mm	2000	-
1210/3225	0.9 mm	-	8 mm	3000	-
	1.3 mm	-	8 mm	3000	-
	1.4 mm	-	8 mm	2000	-
	1.6 mm	-	8 mm	2000	-
1812/4532	1.3 mm	-	12 mm	1500	-
	1.4 mm	-	12 mm	1000	-
	1.6 mm	-	12 mm	-	4000
	2.3 mm	-	12 mm	-	3000
2220/5750	1.3 mm	-	12 mm	1500	-
	1.4 mm	-	12 mm	1000	-
	2.0 mm	_	12 mm	-	3000
	2.3 mm	_	12 mm	-	3000
3225	3.2 mm	-	16 mm	-	1000
	4.5 mm	-	16 mm	-	1000
4032	3.2 mm	—	16 mm	-	1000
	4.5 mm	-	16 mm	-	1000



Telecom series

<u>SMD</u>

2 Delivery mode for leaded SHCV varistors

Standard delivery mode for SHCV types is bulk. Alternative taping modes (AMMO pack or taped on reel) are available upon request.

Packing units for:

Туре	Pieces
SR6	2000
SR1 / SR2	1000

For types not listed in this data book please contact EPCOS.



Telecom series

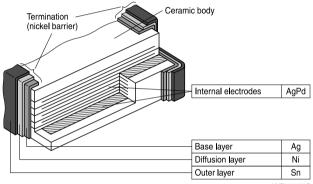
<u>SMD</u>

Soldering directions

1 Terminations

1.1 Nickel barrier termination

The nickel barrier layer of the silver/nickel/tin termination prevents leaching of the silver base metallization layer. This allows great flexibility in the selection of soldering parameters. The tin prevents the nickel layer from oxidizing and thus ensures better wetting by the solder. The nickel barrier termination is suitable for all commonly-used soldering methods.



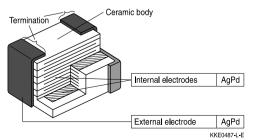
KKE0484-W-E

Multilayer CTVS: Structure of nickel barrier termination

1.2 Silver-palladium termination

Silver-palladium terminations are used for the large case sizes 1812 and 2220 and for chips intended for conductive adhesion. This metallization improves the resistance of large chips to thermal shock.

In case of conductive adhesion, the silver-palladium metallization reduces susceptibility to corrosion. Silver-palladium termination can be used for smaller case sizes (only chip) for hybrid applications as well. The silver-palladium termination is not approved for lead-free soldering.



Multilayer varistor: Structure of silver-palladium termination

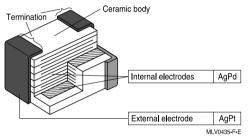


Telecom series

<u>SMD</u>

1.3 Silver-platinum termination

Silver-platinum terminations are mainly used for the large case sizes 1812 and 2220. The silverplatinum termination is approved for reflow soldering, SnPb soldering and lead-free soldering with a silver containing solder paste. In case of SnPb soldering, a solder paste Sn62Pb36Ag2 is recommended. For lead-free reflow soldering, a solder paste SAC, e.g. Sn95.5Ag3.8Cu0.7, is recommended.

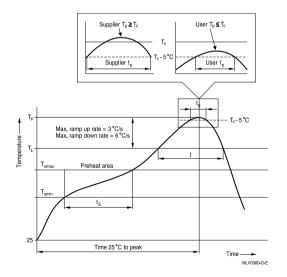


Multilayer varistor: Structure of silver-platinum termination

2 Recommended soldering temperature profiles

2.1 Reflow soldering temperature profile

Recommended temperature characteristic for reflow soldering following JEDEC J-STD-020D



Please read *Cautions and warnings* and *Important notes* at the end of this document.

Telecom series

<u>SMD</u>

Profile feature		Sn-Pb eutectic assembly	Pb-free assembly
Preheat and soak			
- Temperature min	T_{smin}	100 °C	150 °C
- Temperature max	T _{smax}	150 °C	200 °C
- Time	$t_{\mbox{\tiny smin}}$ to $t_{\mbox{\tiny smax}}$	60 120 s	60 180 s
Average ramp-up rate	$\rm T_{smax}$ to $\rm T_{p}$	3 °C/ s max.	3 °C/ s max.
Liquidous temperature	TL	183 °C	217 °C
Time at liquidous	tL	60 150 s	60 150 s
Peak package body temperature	T _p ¹⁾	220 °C 235 °C ²⁾	245 °C 260 °C ²⁾
Time $(t_P)^{3)}$ within 5 °C of specified classification temperature (T_c)		20 s ³⁾	30 s ³⁾
Average ramp-down rate	T_p to T_{smax}	6 °C/ s max.	6 °C/ s max.
Time 25 °C to peak temperature		maximum 6 min	maximum 8 min

1) Tolerance for peak profile temperature (T_P) is defined as a supplier minimum and a user maximum.

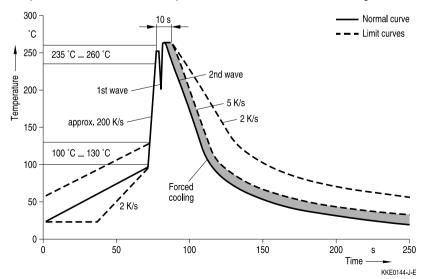
2) Depending on package thickness. For details please refer to JEDEC J-STD-020D.

3) Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.

Note: All temperatures refer to topside of the package, measured on the package body surface. Number of reflow cycles: 3

2.2 Wave soldering temperature profile

Temperature characteristics at component terminal with dual-wave soldering



Please read *Cautions and warnings* and *Important notes* at the end of this document.



Telecom series

<u>SMD</u>

2.3 Lead-free soldering processes

EPCOS multilayer CTVS with AgNiSn termination are designed for the requirements of lead-free soldering processes only.

Soldering temperature profiles to JEDEC J-STD-020D, IEC 60068-2-58 and ZVEI recommendations.

3 Recommended soldering methods - type-specific releases by EPCOS

3.1 Overview

		Reflow soldering		Wave solderi	Wave soldering	
Туре	Case size	SnPb	Lead-free	SnPb	Lead-free	
CT / CD	0201/0402	Approved	Approved	No	No	
CT / CD	0603 2220	Approved	Approved	Approved	Approved	
CN	0603 2220	Approved	No	Approved	No	
CNK2	1812, 2220	Approved	Approved	No	No	
Arrays	0405 1012	Approved	Approved	No	No	
ESD/EMI filters	0405, 0508	Approved	Approved	No	No	
CU	3225, 4032	Approved	Approved	Approved	Approved	
SHCV	-	No	No	Approved	Approved	

3.2 Nickel barrier and AgPt terminated multilayer CTVS

All EPCOS MLVs with nickel barrier and AgPt termination are suitable and fully qualiyfied for leadfree soldering. The nickel barrier layer is 100% matte tin-plated.

3.3 Silver-palladium terminated MLVs

AgPd-terminated MLVs are mainly designed for conductive adhesion technology on hybrid material. Additionally MLVs with AgPd termination are suitable for reflow and wave soldering with SnPb solder.

Note:

Lead-free soldering is not approved for MLVs with AgPd termination.

3.4 Silver-platinum terminated MLVs

The silver-platinum termination is approved for reflow soldering, SnPb soldering and lead-free with a silver containing solder paste. In case of SnPb soldering, a solder paste Sn62Pb36Ag2 is recommended. For lead-free reflow soldering, a solder paste SAC, e.g. Sn95.5Ag3.8Cu0.7, is recommended.



Telecom series

<u>SMD</u>

3.5 Tinned copper alloy

All EPCOS CU types with tinned termination are approved for lead-free and SnPb soldering.

3.6 Tinned iron wire

All EPCOS SHCV types with tinned termination are approved for lead-free and SnPb soldering.

4 Solder joint profiles / solder quantity

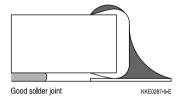
4.1 Nickel barrier termination

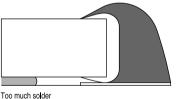
If the meniscus height is too low, that means the solder quantity is too low, the solder joint may break, i.e. the component becomes detached from the joint. This problem is sometimes interpreted as leaching of the external terminations.

If the solder meniscus is too high, i.e. the solder quantity is too large, the vise effect may occur. As the solder cools down, the solder contracts in the direction of the component. If there is too much solder on the component, it has no leeway to evade the stress and may break, as in a vise.

The figures below show good and poor solder joints for dual-wave and infrared soldering.

4.1.1 Solder joint profiles for nickel barrier termination - dual-wave soldering

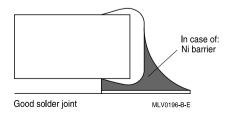


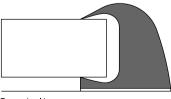


Pad geometry too large, not soldered in preferred direction KKE0288-H-E

Good and poor solder joints caused by amount of solder in dual-wave soldering.

4.1.2 Solder joint profiles for nickel barrier termination / silver-palladium / silver-platinum termination - reflow soldering





Too much solder Pad geometry too large

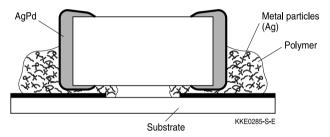
KKE0071-A-E

⇔TDK

SMD disk varistors (CU varistors) Telecom series SMD In case of: AgPd/AgPt Ni-Barrier Good solder joint KKE0070-2-E KKE0070-2-E

Good and poor solder joints caused by amount of solder in reflow soldering.

5 Conductive adhesion



Attaching surface-mounted devices (SMDs) with electrically conductive adhesives is a commercially attractive method of component connection to supplement or even replace conventional soldering methods.

Electrically conductive adhesives consist of a non-conductive plastic (epoxy resin, polyimide or silicon) in which electrically conductive metal particles (gold, silver, palladium, nickel, etc) are embedded. Electrical conduction is effected by contact between the metal particles.

Adhesion is particularly suitable for meeting the demands of hybrid technology. The adhesives can be deposited ready for production requirements by screen printing, stamping or by dispensers. As shown in the following table, conductive adhesion involves two work operations fewer than soldering.

Reflow soldering	Wave soldering	Conductive adhesion
Screen-print solder paste	Apply glue dot	Screen-print conductive adhesive
Mount SMD	Mount SMD	Mount SMD
Predry solder paste	Cure glue	Cure adhesive
Reflow soldering	Wave soldering	Inspect
Wash	Wash	
Inspect	Inspect	



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A further advantage of adhesion is that the components are subjected to virtually no temperature shock at all. The curing temperatures of the adhesives are between 120 °C and 180 °C, typical curing times are between 30 minutes and one hour.

The bending strength of glued chips is, in comparison with that of soldered chips, higher by a factor of at least 2, as is to be expected due to the elasticity of the glued joints.

The lower conductivity of conductive adhesive may lead to higher contact resistance and thus result in electrical data different to those of soldered components. Users must pay special attention to this in RF applications.

6	Solderability tests
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Test	Standard	Test conditions Sn-Pb soldering	Test conditions Pb-free soldering	Criteria/ test results
Wettability	IEC 60068-2-58	Immersion in 60/40 SnPb solder using non-activated flux at 215 \pm 3 °C for 3 \pm 0.3 s	Immersion in Sn96.5Ag3.0Cu0.5 solder using non- or low activated flux at 245 ± 5 °C for 3 ± 0.3 s	Covering of 95% of end termination, checked by visual inspection
Leaching resistance	IEC 60068-2-58	Immersion in 60/40 SnPb solder using mildly activated flux without preheating at 260 ± 5 °C for 10 ± 1 s	Immersion in Sn96.5Ag3.0Cu0.5 solder using non- or low activated flux without preheating at 255 ± 5 °C for 10 ± 1 s	No leaching of contacts
Thermal shock (solder shock)		Dip soldering at 300 °C/5 s	Dip soldering at 300 °C/5 s	No deterioration of electrical parameters. Capacitance change: $\leq \pm 15\%$
Tests of resistance to soldering heat for SMDs	IEC 60068-2-58	Immersion in 60/40 SnPb for 10 s at 260 °C	Immersion in Sn96.5Ag3.0Cu0.5 for 10 s at 260 °C	Change of varistor voltage: $\leq \pm 5\%$
Tests of resistance to soldering heat for radial leaded components (SHCV)	IEC 60068-2-20	Immersion of leads in 60/40 SnPb for 10 s at 260 °C	Immersion of leads in Sn96.5Ag3.0Cu0.5 for 10 s at 260 °C	Change of varistor voltage: $\leq \pm 5\%$ Change of capacitance X7R: $\leq -5/+10\%$



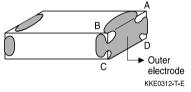
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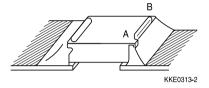
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Note:

Leaching of the termination

Effective area at the termination might be lost if the soldering temperature and/or immersion time are not kept within the recommended conditions. Leaching of the outer electrode should not exceed 25% of the chip end area (full length of the edge A-B-C-D) and 25% of the length A-B, shown below as mounted on substrate.





As mounted on substrate

As a single chip

7 Notes for proper soldering

7.1 Preheating and cooling

According to JEDEC J-STD-020D. Please refer to chapter 2.

7.2 Repair / rework

Manual soldering with a soldering iron must be avoided, hot-air methods are recommended for rework purposes.

7.3 Cleaning

All environmentally compatible agents are suitable for cleaning. Select the appropriate cleaning solution according to the type of flux used. The temperature difference between the components and cleaning liquid must not be greater than 100 °C. Ultrasonic cleaning should be carried out with the utmost caution. Too high ultrasonic power can impair the adhesive strength of the metal-lized surfaces.

7.4 Solder paste printing (reflow soldering)

An excessive application of solder paste results in too high a solder fillet, thus making the chip more susceptible to mechanical and thermal stress. Too little solder paste reduces the adhesive strength on the outer electrodes and thus weakens the bonding to the PCB. The solder should be applied smoothly to the end surface.



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7.5 Adhesive application

Thin or insufficient adhesive causes chips to loosen or become disconnected during curing. Low viscosity of the adhesive causes chips to slip after mounting. It is advised to consult the manufacturer of the adhesive on proper usage and amounts of adhesive to use.

7.6 Selection of flux

Used flux should have less than or equal to 0.1 wt % of halogenated content, since flux residue after soldering could lead to corrosion of the termination and/or increased leakage current on the surface of the component. Strong acidic flux must not be used. The amount of flux applied should be carefully controlled, since an excess may generate flux gas, which in turn is detrimental to sol-derability.

7.7 Storage of CTVSs

Solderability is guaranteed for one year from date of delivery for multilayer varistors, CeraDiodes and ESD/EMI filters (half a year for chips with AgPd and AgPt terminations) and two years for SHCV and CU components, provided that components are stored in their original packages.

Storage temperature:−25 °C to +45 °CRelative humidity:≤75% annual average, ≤95% on 30 days a year

The solderability of the external electrodes may deteriorate if SMDs and leaded components are stored where they are exposed to high humidity, dust or harmful gas (hydrogen chloride, sulfurous acid gas or hydrogen sulfide).

Do not store SMDs and leaded components where they are exposed to heat or direct sunlight. Otherwise the packing material may be deformed or SMDs/ leaded components may stick together, causing problems during mounting.

After opening the factory seals, such as polyvinyl-sealed packages, it is recommended to use the SMDs or leaded components as soon as possible.

7.8 Placement of components on circuit board

Especially in the case of dual-wave soldering, it is of advantage to place the components on the board before soldering in that way that their two terminals do not enter the solder bath at different times.

Ideally, both terminals should be wetted simultaneously.

7.9 Soldering cautions

- An excessively long soldering time or high soldering temperature results in leaching of the outer electrodes, causing poor adhesion and a change of electrical properties of the varistor due to the loss of contact between electrodes and termination.
- Wave soldering must not be applied for MLVs designated for reflow soldering only.
- Keep the recommended down-cooling rate.



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7.10 Standards

CECC 00802 IEC 60068-2-58 IEC 60068-2-20 JEDEC J-STD-020D



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Symbols and terms

Symbol	Term
Cline,typ	Typical capacitance per line
C _{max}	Maximum capacitance
C _{min}	Minimum capacitance
C _{nom}	Nominal capacitance
ΔC_{nom}	Tolerance of nominal capacitance
C _{typ}	Typical capacitance
$f_{\text{cut-off,min}}$	Minimum cut-off frequency
I	Current
I _{clamp}	Clamping current
I _{leak}	Leakage current
I _{leak,typ}	Typical leakage current
I _{PP}	Peak pulse current
I _{surge,max}	Maximum surge current (also termed peak current)
LCT	Lower category temperature
L _{typ}	Typical inductance
$P_{diss,max}$	Maximum power dissipation
P _{PP}	Peak pulse power
R _{ins}	Insulation resistance
R _{min}	Minimum resistance
Rs	Resistance per line
T _A	Ambient temperature
T_{op}	Operating temperature
T _{stg}	Storage temperature
t _r	Duration of equivalent rectangular wave
t _{resp}	Response time
UCT	Upper category temperature
V	Voltage
$V_{BR,min}$	Minimum breakdown voltage
$V_{\text{clamp,max}}$	Maximum clamping voltage
$V_{\text{DC,max}}$	Maximum DC operating voltage (also termed working voltage)
$V_{\text{ESD,air}}$	Air discharge ESD capability
$V_{\text{ESD,contact}}$	Contact discharge ESD capability
V _{jump}	Maximum jump start voltage